

Sheet 1 of 2

|  |  |   |             |
|--|--|---|-------------|
| Form PTO-1449 U.S. Department of Commerce<br>Patent and Trademark Office         |  | Atty. Docket No.:<br>FMW-GG-CIP (CZ 22-CIP) | Serial No.: |
| <b>LIST OF PRIOR ART CITED BY APPLICANT</b><br>(Use several sheets if necessary) |  | Applicant:<br>Dr. Frederik Bijkerk et al.   |             |
|  |  | Filing Date:<br>November 12, 2003           | Group:      |

**U.S. PATENT DOCUMENTS**

| Examiner Initial |    | Document Number | Date           | Name            | Class | Subclass | Filing date if appropriate |
|------------------|----|-----------------|----------------|-----------------|-------|----------|----------------------------|
| GAB              | AA | 5,052,033       | September 1991 | Ikeda et al.    |       |          |                            |
|                  | AB | 5,265,143       | November 1993  | Early et al.    |       |          |                            |
|                  | AC | 5,433,988       | July 18, 1995  | Fukuda et al.   |       |          |                            |
|                  | AD | 5,760,981       | June 2, 1998   | Gillich         |       |          |                            |
|                  | AE | 5,958,605       | September 1999 | Montcalm et al. |       |          |                            |
|                  | AF | 5,310,603       | May 10, 1994   | Fukuda et al.   |       |          |                            |
| GAB              | AG | 6,160,867       | December 2000  | Murakami        |       |          |                            |
|                  | AH |                 |                |                 |       |          |                            |
|                  | AI |                 |                |                 |       |          |                            |
|                  | AJ |                 |                |                 |       |          |                            |
|                  | AK |                 |                |                 |       |          |                            |

**FOREIGN PATENT DOCUMENTS**

|     |    | Document Number | Date               | Country | Class | Subclass | Translation Yes No |
|-----|----|-----------------|--------------------|---------|-------|----------|--------------------|
| GAB | AL | WO 99/24851     | May 20, 1999       | WIPO    |       |          |                    |
| J   | AM | 08122496        | May 17, 1996       | JP      |       |          |                    |
|     | AN | 06273596        | September 30, 1994 | JP      |       |          |                    |
| GAB | AO | 1 065 568 A2    | January 3, 2001    | EP      |       |          |                    |
|     | AP |                 |                    |         |       |          |                    |

**OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)**

|     |    |  |
|-----|----|--|
| GAB | AR | J.H. Underwood et al., <i>Tarnishing of Mo/Si multilayer x-ray mirrors</i> , Applied Optics, vol. 32, 1993, p. 6985-6990                           |
| J   | AS | C. Montcalm et al., <i>Multilayer reflective coatings for extreme-ultraviolet lithography</i> , SPIE, vol. 3331, (1998) p. 42-51                   |
| GAB | AT | M. Cilia et al., <i>Ni/Si based multilayer for the reflection of soft x rays in the "water window"</i> , J. Appl-Phys., 82 (9), 1997, p. 4137-4142 |

EXAMINER

DATE CONSIDERED

3/15/06

\*EXAMINER: Initial if reference considered. Whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

| Form PTO-1449 U.S. Department of Commerce<br>Patent and Trademark Office  |    |                 |   | Atty. Docket No.:           | Serial No.: |          |                            |
|---|----|-----------------|---|-----------------------------|-------------|----------|----------------------------|
|   |    |                 |   | FMW-GG-CIP (CZ 22-CIP)      |             |          |                            |
| <b>LIST OF PRIOR ART CITED BY APPLICANT</b><br>(Use several sheets if necessary)  |    |                 |   | Applicant:                  |             |          |                            |
|   |    |                 |   | Dr. Frederik Bijkerk et al. |             |          |                            |
|   |    |                 |   | Filing Date:                | Group:      |          |                            |
|   |    |                 |   | November 12, 2003           |             |          |                            |
| <b>U.S. PATENT DOCUMENTS</b>  |    |                 |   |                             |             |          |                            |
| Examiner Initial  |    | Document Number | Date  | Name                        | Class       | Subclass | Filing date if appropriate |
|   | AA |                 |   |                             |             |          |                            |
|   | AB |                 |   |                             |             |          |                            |
|   | AC |                 |   |                             |             |          |                            |
|   | AD |                 |   |                             |             |          |                            |
|   | AE |                 |   |                             |             |          |                            |
|   | AF |                 |   |                             |             |          |                            |
|   | AG |                 |   |                             |             |          |                            |
|   | AH |                 |   |                             |             |          |                            |
|   | AI |                 |   |                             |             |          |                            |
|   | AJ |                 |   |                             |             |          |                            |
|   | AK |                 |   |                             |             |          |                            |
| <b>FOREIGN PATENT DOCUMENTS</b>   |    |                 |   |                             |             |          |                            |
|   |    | Document Number | Date  | Country                     | Class       | Subclass | Translation Yes No         |
|   | AL |                 |   |                             |             |          |                            |
|   | AM |                 |   |                             |             |          |                            |
|   | AN |                 |   |                             |             |          |                            |
|   | AO |                 |   |                             |             |          |                            |
|   | AP |                 |   |                             |             |          |                            |
| <b>OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)</b>   |    |                 |   |                             |             |          |                            |
| <i>GAB</i>  | AR |                 | H. Takenaka et al., <i>Design and fabrication of highly heat-resistant Mo/Si multilayer soft X-ray mirrors with interleaved barrier layers</i> , J. Synchrotron Rad. (1998) 5. p. 708-710 |                             |             |          |                            |
| <i>EAB</i>  | AS |                 | E.J. Puik et al., <i>Ion bombardment of X-ray multilayer coatings: comparison of ion etching and ion assisted deposition</i> , Applied Surface Science 47 (1991) p. 251-260               |                             |             |          |                            |
|   | AT |                 |   |                             |             |          |                            |
| EXAMINER <i>R. B. B.</i>  |    |                 | DATE CONSIDERED <i>3/15/04</i>  |                             |             |          |                            |
| *EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 809; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. |    |                 |   |                             |             |          |                            |